



Laboratoria De Nayer v.z.w.  
Department of Electronics  
Section E.M.C.

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Photo's test setup	
<b>Product</b>	DSRFID type D
<b>LDN Number</b>	LDN5031
<b>Date of issue</b>	2024-09-24
<b>Standard</b>	FCC part 15 subpart C
<b>EMC report</b>	PCC-RAD-6113

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The results refer to the described sample or equipment under test only.  
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In case the customer wants to refer to his appeal to our accredited laboratories, he will use the following orequivalent sentence: "Tested by Laboratoria De Nayer, E.M.C.department, accredited by BELAC for EMC-immunity and EMC-emission under registration number 041-TEST".

photo : conducted emission set-up (0.15-30MHz)

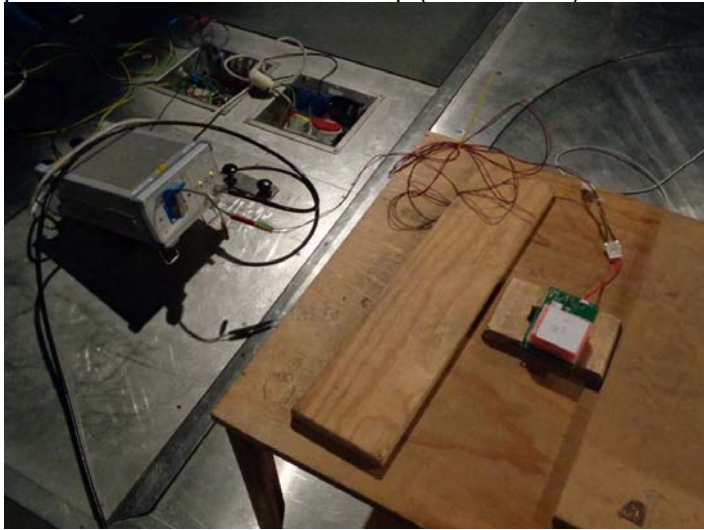


photo 2: radiated emission set-up (9k-30MHz)



Photo : radiates emission (30-50MHz)

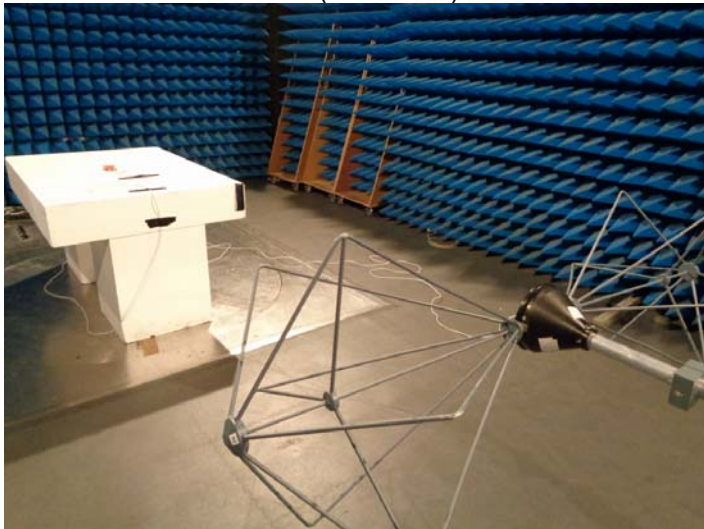


Photo : radiates emission (30-1000MHz)



Photo : EUT in thermal chamber

